Se	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/826,109	NISHIO ET AL.	
Examiner	Art Unit	
Philip C. Lee	2152	

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
709	203,217	10/11/2006	PL
713	193	10/11/2006	PL
370	338	10/11/2006	PL
709/219,222,226		10/11/2006	PL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Consulted with SPE: Bunjob Jaroenchonwanit	10/3/2006	PL
Keywords Search in EAST	10/2/2006	PL
Keywords Search 709/217 in EAST	10/3/2006	PĽ
ACM/IEEE Search	10/11/2006	PL
Google search	10/11/2006	Pr.
Search 709/203, 217, 219, 222, 226; 713/193; 370/338 in PG-Pubs	10/11/2006	PL
Inventor Named Search	10/3/2006	PL
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